AMENDMENTS TO THE CLAIMS:

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

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Claim 1 (previously presented): A quantum semiconductor device comprising: a first semiconductor layer formed over a substrate and having a two-dimensional carrier gas 2 formed in; 3 a quantum dot formed over the first semiconductor layer; a second semiconductor layer formed over the first semiconductor layer, burying the quantum 5 dot; a dot-shaped structure formed on the surface of the second semiconductor layer at a position 7 above the quantum dot; and 8 oxide layers formed on both sides of the dot-shaped structure on the upper surface of the 9 second semiconductor layer. 10 Claim 2 (original): A quantum semiconductor device according to claim 1, wherein 1

the dot-shaped structure is caused to form on the surface of the second semiconductor layer

at a position above the quantum dot due to crystal strains generated in the surface of the second 3 semiconductor layer due to the presence of the quantum dot. 4 Claim 3 (original): A quantum semiconductor device according to claim 1, wherein 1 the quantum dot is in a three-dimensionally grown island self-assembled by S-K mode. 2 Claim 4 (original): A quantum semiconductor device according to claim 1, wherein 1 the dot-shaped structure is in a three-dimensionally grown island self-assembled by S-K 2 mode. 3 Claim 5 (currently amended): A quantum semiconductor device according to claim 1, wherein 2 [[a]] depletion region is regions are formed due to the presence of the oxide layer in a region 3 regions of the first semiconductor layer, which [[is]] are below the oxide layer layers, and 4 a channel region is defined by the depletion region the depletion regions define a channel 5 region. 6 Claim 6 (original): A quantum semiconductor device according to claim 5, further comprising: 2

source/drain regions connected to both ends of the channel region.

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1	Claim 7 (original): A quantum semiconductor device according to claim 1, further
2	comprising:
3	a gate electrode connected to the dot-shaped structure.
1	Claim 8 (original): A quantum semiconductor device according to claim 1, wherein
2	a distance between the two-dimensional carrier gas and the quantum dot is 5 nm or less.
1	Claim 9 (original): A quantum semiconductor device according to claim 1, wherein
2	the dot-shaped structure is in another quantum dot or an anti-dot.
1	Claim 10 (original): A quantum semiconductor device according to claim 1, wherein
2	at least a part of the dot-shaped structure is oxidized.
1	Claim 11 (previously presented): A method for fabricating a quantum semiconductor device
2	comprising the steps of:
3	forming over a substrate a first semiconductor layer with a two-dimensional carrier gas
4	formed in;
5	forming a quantum dot over the first semiconductor layer;
6	forming a second semiconductor layer, burying the quantum dot;

forming a dot-shaped structure on the surface of the second semiconductor at a position above the quantum dot due to strains generated in the surface of the second semiconductor layer due to the presence of the quantum dot; and forming oxide layers on the upper surface of the second semiconductor layer on both side of the dot-shaped structure with the dot-shaped structure as a mark. Claim 12 (withdrawn): A method for fabricating a quantum semiconductor device according to claim 11, further comprising, after the step of forming the oxide layer, the step of forming source/drain regions with the oxide layer as a mark. Claim 13 (withdrawn): A method for fabricating a quantum semiconductor device according to claim 11, wherein in the step of forming the quantum dot, the quantum dot in a three-dimensional grown island is self-assembled by S-K mode. Claim 14 (withdrawn): A method for fabricating a quantum semiconductor device according to claim 11, wherein in the step of forming the dot-shaped structure, the dot-shaped structure in a

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three-dimensional grown island is self-assembled by S-K mode.

1 Claim 15 (withdrawn): A method for fabricating a quantum semiconductor device according to claim 11, wherein . 2 in the step of forming an oxide layer, the oxide layer is formed by bringing a needle-shaped 3 conductor close to the surface of the second semiconductor layer and applying a voltage between the 4 needle-shaped conductor and the substrate. 5 Claim 16 (withdrawn): A method for fabricating a quantum semiconductor device according 1 to claim 15, wherein 2 the needle-shaped conductor is a probe of an atomic force microscope. 3